A probe for probing test points on a target board uses a printed circuit board (PCB) having a plurality of signal routes for routing signals to a test instrument. The probe also has a plurality of spring pins for probing the test points on the target board. Each of the spring pins is disposed perpendicularly to the PCB, and is electrically coupled to at least one signal route of the PCB. By way of example, the spring pins may be fit into holes in the PCB or, alternately, they may be electrically coupled to signal routes of a second PCB that is perpendicularly abutted to the first PCB. Methods for making and using such probes are also disclosed.
OTHER PUBLICATIONS


* cited by examiner
FORM A ROW OF VIAS IN A FIRST PCB

CUT THE FIRST PCB ALONG THE ROW OF VIAS, THEREBY EXPOSING CROSS-SECTIONS OF THE VIAS AT A CUT EDGE OF THE FIRST PCB

CUT THE FIRST PCB ALONG THE CUT EDGE TO FORM FIRST AND SECOND SETS OF EDGE PADS FROM THE VIA CROSS-SECTIONS

ELECTRICALLY COUPLE A PLURALITY OF SPRING PINS TO A PLURALITY OF SIGNAL ROUTES OF THE FIRST PCB


FIG. 8
FIG. 9

FIG. 10

FIG. 11

SELECT TEST PROBE

MOVE TEST PROBE OVER TARGET BOARD TO SEAT AN ALIGNMENT MECHANISM OF THE TEST PROBE TO A CORRESPONDING ALIGNMENT MECHANISM OF THE TARGET BOARD

APPLY PRESSURE TO AT LEAST ONE OF THE I) TEST PROBE OR II) TARGET BOARD TO cause A plurality OF SPRING PINS OF THE TEST PROBE TO ENGAGE TEST POINTS ON THE TARGET BOARD

ROUTE SIGNALS FROM THE TEST POINTS TO A TEST INSTRUMENT VIA THE TEST PROBE

FIG. 12